INDIAN INSTITUTE OF TECHNOLOGY BOMBAY
MATERIALS MANAGEMENT DIVISION
Powai, Mumbai 400076.

PR No. 1000053092 RFx No. 6100002811

Technical Specification: CMC for Helios 05 UC (Focused Ion Beam – Scanning electron Microscope (FIB-SEM))

Sr. No.	Item Description	Detailed Technical Specification	Technical Compliance (Yes / No)	Additional Information (if any)
1.	Helios 5 UC	FIB-SEM, with Electron column, Ion column, GIS, EDS, STEM, and Incolumn detector, EasyLift NanoManipulator.		
2	Resolution	TLD, UC-mode ON, 1 kV, measured value 0.7 nm TLD, UC-mode ON, 2 kV, measured value 0.6 nm ICD, UC-mode ON, 500 V, measured value 1.0 nm Measured resolution for Ion column 4.0 nm		
3	Stage 6-inch piezo	Piexo 150mm X-75+75mm Y-75+75mm Z-10+20mm R-360° T--10° to 60° Maximum sample weight- 1000g		

Scope of Work

1. **Duration**
The contract shall be valid for a period of one (1) year from the date of commencement as mentioned in the Service order.

2. **Preventive & Breakdown Maintenance**
The contractor should carry out timely preventive maintenance to ensure optimal performance and longevity of the instruments. In addition to

preventive maintenance, breakdown maintenance visits should be provided as and when required, without undue delay.

3. **Genuine Parts**
   All replacement parts used during maintenance or repair should be new and genuine parts approved by the manufacturer.

4. **Qualified Service Personnel**
   Services should be rendered only by trained, qualified, and certified Field Service Engineers with adequate experience in handling the specified equipment.

5. **Priority Service Response**
   The contractor should provide priority response to service calls raised by the purchaser.

6. **Payment Terms**
   Payment on six monthly bases in two equal instalments after completion of the service subject to their satisfactory performance to be certified by the Indentor.